



## N-Channel Enhancement-Mode Vertical DMOS FETs

### Ordering Information

$BV_{DSS} / BV_{DGS}$	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package	
				TO-92	SOW-20*
40V	0.75Ω	4.0A	1.6V	TN0604N3	—
40V	1.0Ω	4.0A	1.6V	—	TN0604WG

\* Same as SO-20 with 300 mil wide body.

### Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 140pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

### Applications

- ☐ Logic level interfaces – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drives
- ☐ Analog switches
- ☐ General purpose line drivers
- ☐ Telecom switches

### Absolute Maximum Ratings

Drain-to-Source Voltage	$BV_{DSS}$
Drain-to-Gate Voltage	$BV_{DGS}$
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

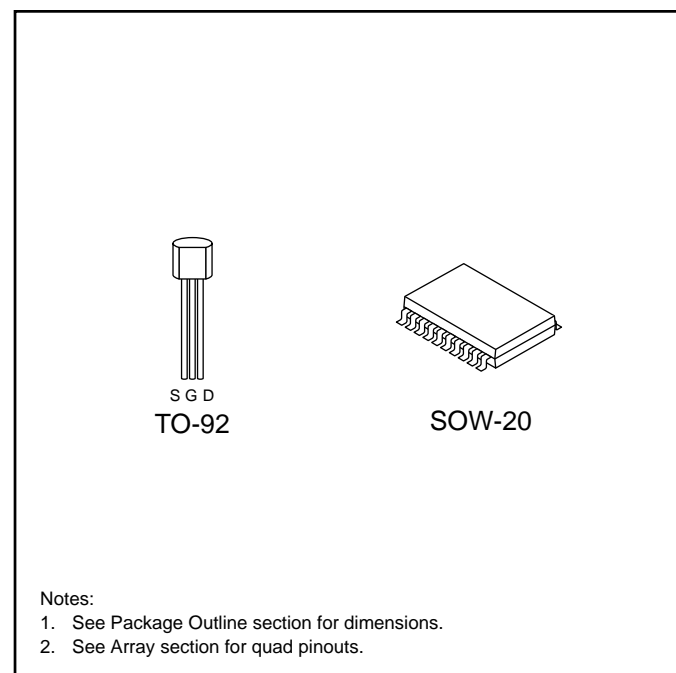
\* Distance of 1.6 mm from case for 10 seconds.

### Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex's vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

### Package Options



## Thermal Characteristics

Package	$I_D$ (continuous)*	$I_D$ (pulsed)	Power Dissipation @ $T_C = 25^\circ\text{C}$	$\theta_{jc}$ $^\circ\text{C/W}$	$\theta_{ja}$ $^\circ\text{C/W}$	$I_{DR}^*$	$I_{DRM}$
TO-92	700mA	4.6A	1W	125	170	700mA	4.6A
SOW-20	Refer to Enhancement Mode MOSFET Arrays Section.						

\*  $I_D$  (continuous) is limited by max rated  $T_J$ .

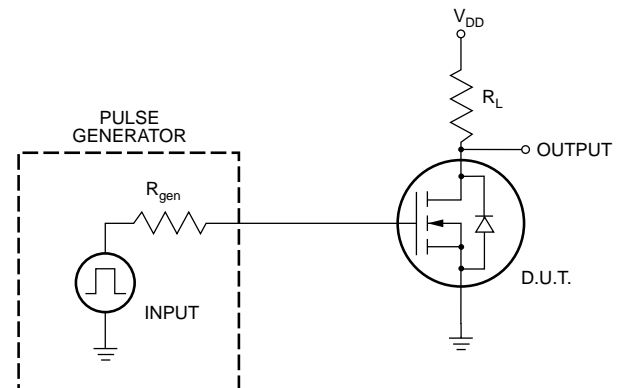
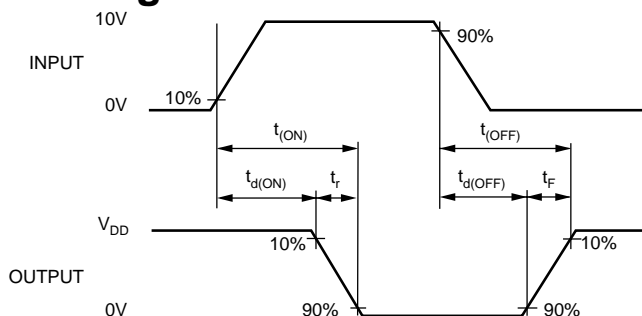
## Electrical Characteristics (@ $25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage		40			V	$V_{GS} = 0V, I_D = 2.0mA$
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	$V_{GS} = V_{DS}, I_D = 1.0mA$
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-4.5	mV/ $^\circ\text{C}$	$V_{GS} = V_{DS}, I_D = 2.5mA$
$I_{GSS}$	Gate Body Leakage				100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
$I_{DSS}$	Zero Gate Voltage Drain Current				10	$\mu\text{A}$	$V_{GS} = 0V, V_{DS} = \text{Max Rating}$
					1.0	mA	$V_{GS} = 0V, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(ON)}$	ON-State Drain Current		1.5	2.1		A	$V_{GS} = 5V, V_{DS} = 20V$
			4.0	7.0			$V_{GS} = 10V, V_{DS} = 20V$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	TO-92/SOW-20		1.0	1.6	$\Omega$	$V_{GS} = 5V, I_D = 0.75A$
		TO-92		0.6	0.75	$\Omega$	$V_{GS} = 10V, I_D = 1.5A$
		SOW - 20			1.0		
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.5	0.75	%/ $^\circ\text{C}$	$V_{GS} = 10V, I_D = 1.5A$
$G_{FS}$	Forward Transconductance		0.5	0.8		$\text{S}$	$V_{DS} = 20V, I_D = 1.5A$
$C_{ISS}$	Input Capacitance			140	190	pF	$V_{GS} = 0V, V_{DS} = 20V$ $f = 1 \text{ MHz}$
$C_{OSS}$	Common Source Output Capacitance			75	110		
$C_{RSS}$	Reverse Transfer Capacitance			25	50		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	$V_{DD} = 20V$ $I_D = 0.5A$ $R_{GEN} = 25\Omega$
$t_r$	Rise Time				6.0		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
$t_f$	Fall Time				20		
$V_{SD}$	Diode Forward Voltage Drop			1.2	1.8	V	$V_{GS} = 0V, I_{SD} = 1.5A$
$t_{rr}$	Reverse Recovery Time			300		ns	$V_{GS} = 0V, I_{SD} = 1A$

### Notes:

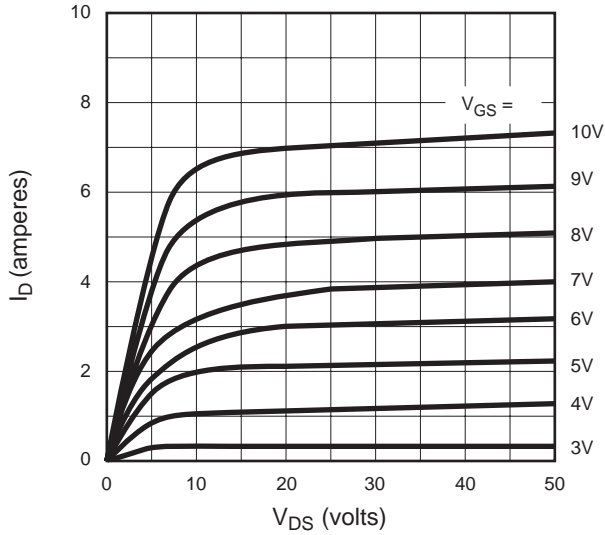
- 1: All D.C. parameters 100% tested at  $25^\circ\text{C}$  unless otherwise stated. (Pulse test: 300 $\mu\text{s}$  pulse, 2% duty cycle.)
- 2: All A.C. parameters sample tested.

## Switching Waveforms and Test Circuit

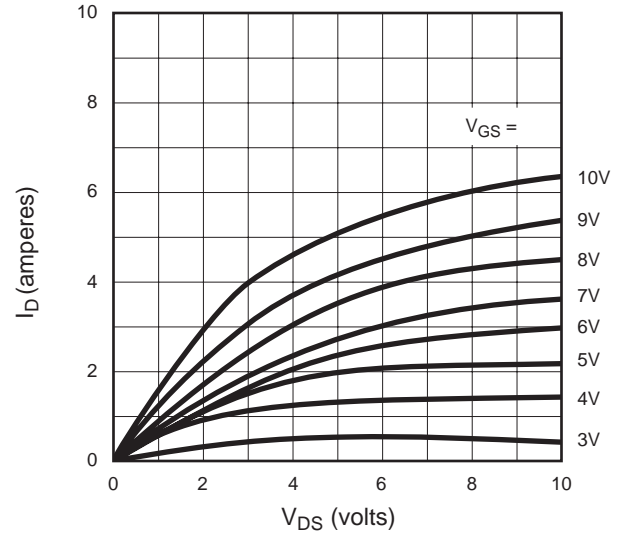


# Typical Performance Curves

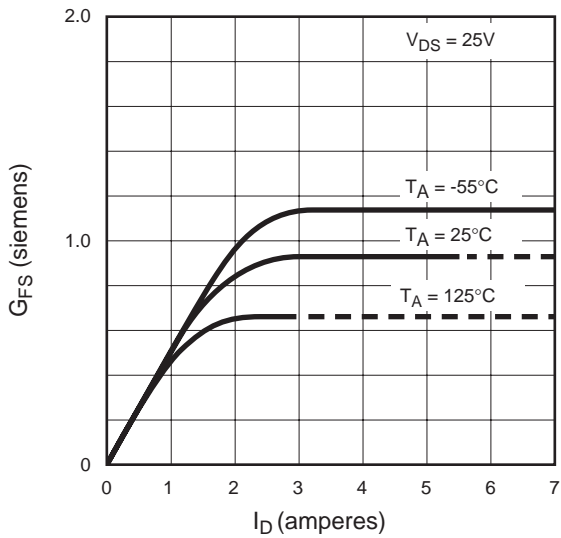
Output Characteristics



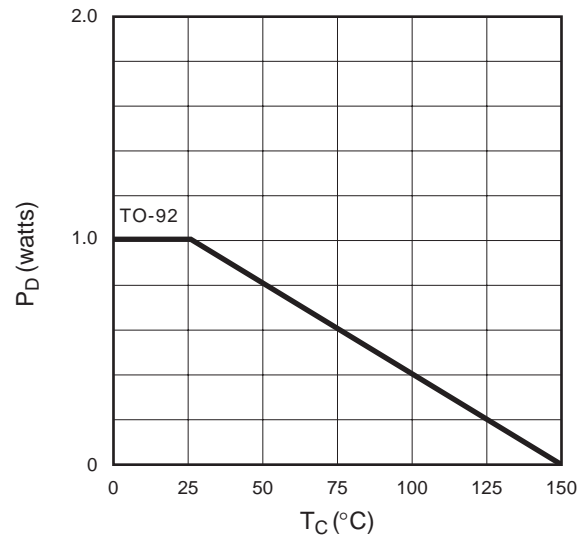
Saturation Characteristics



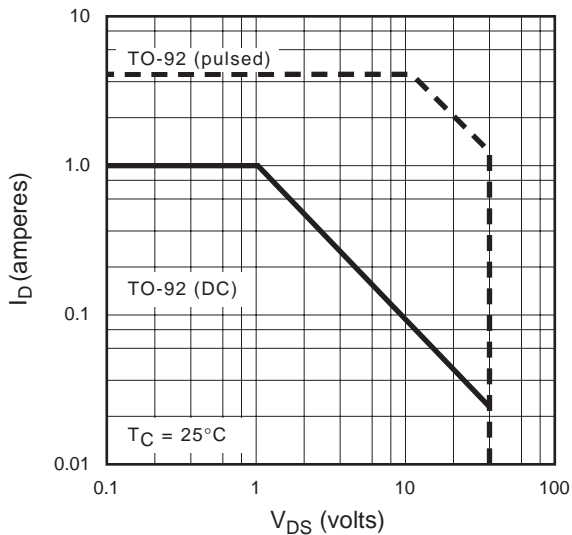
Transconductance vs. Drain Current



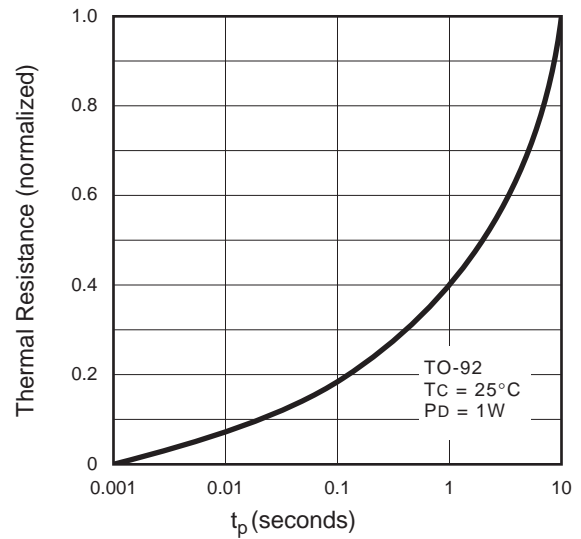
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

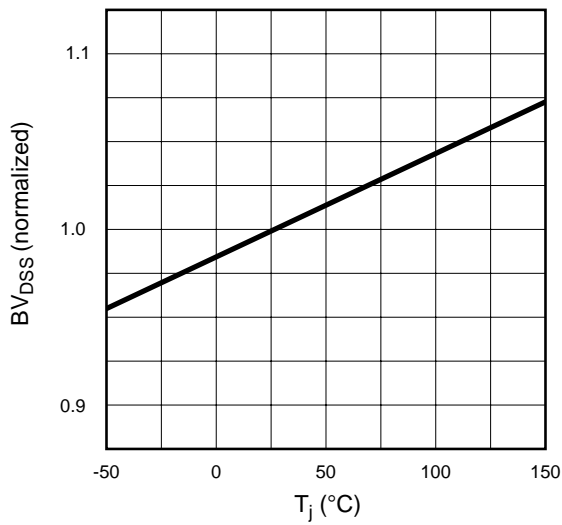


Thermal Response Characteristics

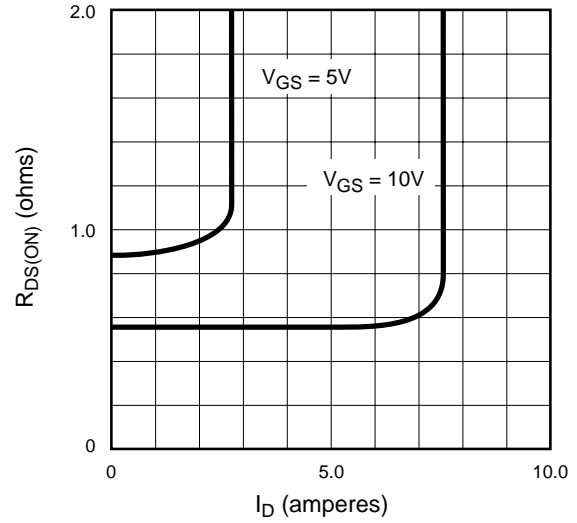


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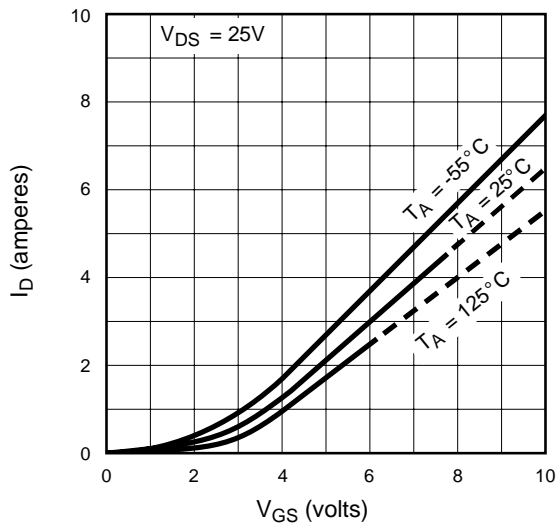
## BV<sub>DSS</sub> Variation with Temperature



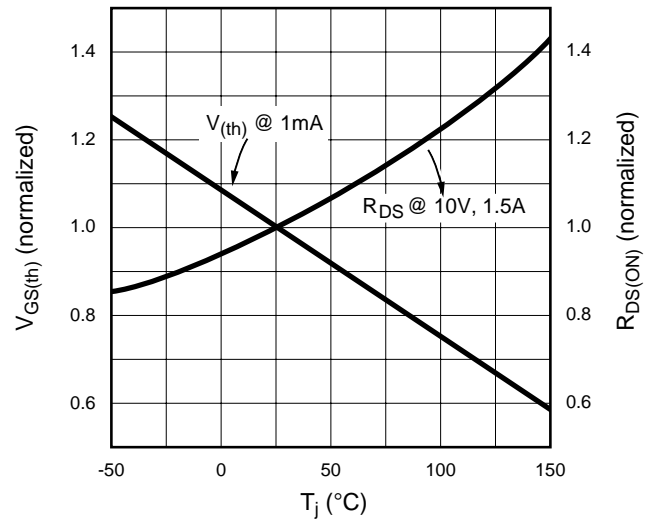
## On-Resistance vs. Drain Current



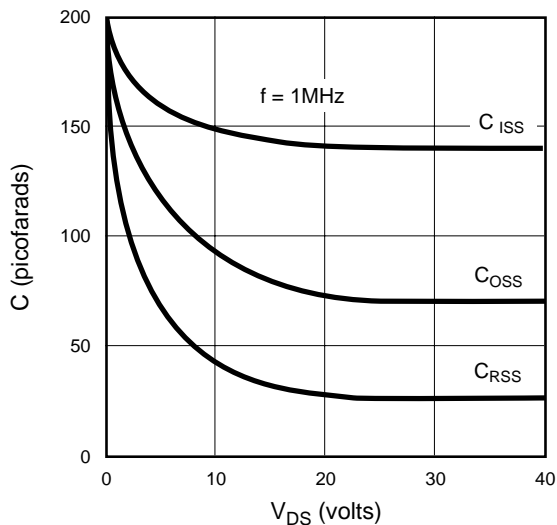
## Transfer Characteristics



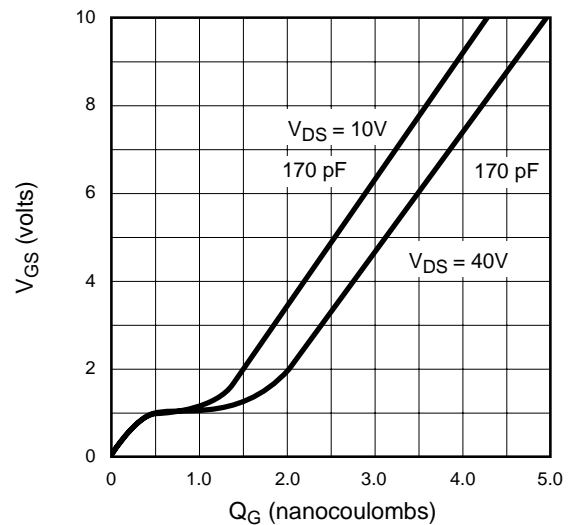
## V<sub>(th)</sub> and R<sub>DS</sub> Variation with Temperature



## Capacitance vs. Drain-to-Source Voltage



## Gate Drive Dynamic Characteristics



02/06/02